Scan chain encryption in Test Standards
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SCAN CHAIN ENCRYPTION IN TEST STANDARDS

Mathieu Da Silva, Marie-Lise Flottes, Giorgio Di Natale, Bruno Rouzeyre

SURREALIST 2018
**Context**

- Test standards
  - IEEE 1149 (JTAG) for board testing
  - IEEE 1500 for cores testing in a SoC
  - IEEE 1687 (IJTAG) for embedded instruments
**Threats**

- **Untrusted devices**
  
  *Rosenfeld et al., Attacks and Defenses for JTAG, IEEE Design & Test 2010*

- **Malicious users**
  
  *(example: scan attacks)*

  *Yang et al., Secure Scan: A Design-for-Test Architecture for Crypto Chips, TCAD’06*
SUMMARY

1) Scan chain encryption

2) State-of-the-art based on test communication encryption

3) Implementation with block cipher

4) Implementation with stream cipher

5) Conclusion
SCAN CHAIN ENCRYPTION

- Solution: test communication encryption

- Input decryption prevents sending desired test data
- Output encryption prevents reading plain test responses
Solution: test communication encryption

- Input decryption prevents sending desired test data
- Output encryption prevents reading plain test responses
- Test/debug only possible by authorized user knowing the secret key
2 types of symmetric cipher: stream and block ciphers
STREAM CIPHER / BLOCK CIPHER

Stream cipher encryption
- Keystream XORed bitwise with the plaintext

Block cipher encryption
- Confusion and diffusion on a block of plaintext

Preference for stream ciphers
- "Naturally" adapted to serial test communication (JTAG, IEEE 1500, IJTAG)
- Smaller area footprint compared to block ciphers
- But ..
Two-times pad: same key and IV re-used => same keystream generated to encrypt different data

⇒ Possible to carry out attacks if requirement is not fit

\[ R_1 \oplus S(IV, Key) \oplus R_2 \oplus S(IV, Key) \]

⇒ Solution: IV generated randomly at each circuit reset

\[ R_1 \oplus S(IV_1, Key) \oplus R_2 \oplus S'(IV_2, Key) \]
SUMMARY

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STREAM-BASED ENCRYPTION ON JTAG INTERFACE

Challenge/Response protocol to encrypt JTAG test communication

1) Challenge C

2) Response as Key

3) Encryption of the JTAG TDR with the keystream $S(IV, Key)$

Requirement not fulfilled
STREAM-BASED ENCRYPTION ON IEEE 1500 INTERFACE

- IEEE 1500 standard
  - Similar as JTAG standard, but for SoC wrappers
  - Parallel test inputs WPI and parallel test outputs WPO

Diagram:
- Core under test
- Scan chain
- IDCODE
- BYP
- IR
- WSI
- BSR
- WPI
- WPO
- Core 1
- Core 2
- Core 3
- WSC
- WSO

01/06/2018
STREAM-BASED ENCRYPTION ON IEEE 1500 INTERFACE

- Encrypt test data on a targeted core (IEEE 1500)
  1) Send the key to the core via specific scan chain non-visible from the others cores

Rosenfeld et al., Security-Aware SoC Test Access Mechanisms, VTS’11
STREAM-BASED ENCRYPTION ON IEEE 1500 INTERFACE

- Encrypt test data on a targeted core (IEEE 1500)
  1) Encrypt the parallel input/output (WPI and WPO)

Rosenfeld et al., Security-Aware SoC Test Access Mechanisms, VTS’11

01/06/2018
STREAM-BASED ENCRYPTION ON IJTAG INTERFACE

- Encryption of Test Data Register associated to Instruments in the IJTAG network

Kan et al., Echeloned IJTAG data protection, AsianHOST 2016.

01/06/2018
OUR PROPOSITION

- Insertion of block or stream ciphers at Scan-In and Scan-Out

- Assumption: original circuit embedded a crypto-core with its key management and storing

- Scan chain encryption solution shares the key management and storing already implemented
SUMMARY

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Implementation on scan chain with 2 PRESENT block ciphers:
- Lightweight (1 PRESENT = 2 139 GE)
- Encryption by 64-bits block size
MODE OF OPERATIONS

- 64 bits encrypted every 32 clock cycles

\[ \Rightarrow \#SFF = P \times 64 \]

\[ \Rightarrow \text{No test time overhead on each pattern} \]
**Mode of Operations**

- U bits = Unused bits

\[ S_1 \]
\[ R + U = 64 \text{ bits} \]

\[ R = \#SFF \mod 64 \]
\[ \text{U bits added} \]

\[ \Rightarrow \#SFF = P \times 64 + R \]

\[ \Rightarrow \text{Loss of U clock cycles per pattern} \]
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STREAM CIPHER-BASED SCAN ENCRYPTION

- Implementation on JTAG:
  - 1 TRIVIUM stream cipher (2016 GE)
  - TRNG to generate random IV
  - New instruction GetIV with a test data register IV

- Mode of operations in 2 phases: initialization and encryption
1) TRNG initialization: reach sufficient entropy to generate random number

INITIALIZATION PHASE
INITIALIZATION PHASE

2) Shift IV in the dedicated Test Data Register
INITIALIZATION PHASE

3) Stream cipher setup

- Test Patterns
- TRNG
- Key Management and Storing
- Scan chain
  - IV
  - IDCODE
  - BYP
  - IR
  - TAP controller
- TDI
- TCK/TMS
- Off-Chip Encryption
- On-Chip Decryption
- On-Chip Encryption
- Off-Chip Decryption

Test Responses
**INITIALIZATION PHASE**

Initialization phase finished => Encryption phase
ENCRYPTION PHASE

○ User sends GETIV instruction

⇒ Shift the content of the IV register out the circuit
**Encryption Phase**

- User can encrypt and decrypt test data with the obtained IV and the shared secret key.
**Time for the initialization process**

- $T_{TRNG\_init}$ to initialize the TRNG
- 80 clock cycles to shift the $IV$ in the register
- 1 152 clock cycles for the stream cipher setup

<table>
<thead>
<tr>
<th>Original circuit</th>
<th>Triple-DES</th>
<th>Pipelined AES-128</th>
<th>Pipelined AES-256</th>
<th>RSA 1024</th>
<th>LEON3</th>
</tr>
</thead>
<tbody>
<tr>
<td>Test time*</td>
<td>687 101</td>
<td>1 944 877</td>
<td>4 559 845</td>
<td>39 405 239</td>
<td>11 612 051</td>
</tr>
<tr>
<td>(clock cycles)</td>
<td></td>
<td></td>
<td></td>
<td></td>
<td></td>
</tr>
</tbody>
</table>

**Test time overhead**

<table>
<thead>
<tr>
<th></th>
<th>Block-based solution (%)</th>
<th>Block-based solution (%)</th>
<th>Block-based solution (%)</th>
<th>Block-based solution (%)</th>
<th>Block-based solution (%)</th>
</tr>
</thead>
<tbody>
<tr>
<td></td>
<td>+0.31</td>
<td>+0.81</td>
<td>+0.006</td>
<td>+0.33</td>
<td>+0.004</td>
</tr>
<tr>
<td>Stream-based solution (%)**</td>
<td>+0.18</td>
<td>+0.06</td>
<td>+0.03</td>
<td>+0.003</td>
<td>+0.01</td>
</tr>
</tbody>
</table>

*: Test time considered for a fault coverage of 100%, except for LEON3 where it reaches 70%

**: test time overhead without the initialization of the TRNG
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## COMPARISON BETWEEN BOTH SOLUTIONS

<table>
<thead>
<tr>
<th></th>
<th>Block cipher-based solution (PRESENT)</th>
<th>Stream cipher-based solution (TRIVIUM)</th>
</tr>
</thead>
<tbody>
<tr>
<td><strong>Security</strong></td>
<td></td>
<td></td>
</tr>
<tr>
<td>- Scan attacks</td>
<td>Protected</td>
<td>Protected (two times pad not possible)</td>
</tr>
<tr>
<td>- Malicious core</td>
<td>Protected</td>
<td>Protected</td>
</tr>
<tr>
<td><strong>Cost</strong></td>
<td></td>
<td></td>
</tr>
<tr>
<td>- Area</td>
<td>10 658.96 µm²</td>
<td>5 408.52 µm² (+ 31 200 µm² for TRNG)</td>
</tr>
<tr>
<td>- Test time</td>
<td>Depends on the scan length (multiple or not of the block size)</td>
<td>Clock cycles required for the initialization phase</td>
</tr>
<tr>
<td><strong>Integration</strong></td>
<td></td>
<td></td>
</tr>
<tr>
<td>- Diagnosis &amp; debug</td>
<td>Still possible in-field</td>
<td></td>
</tr>
<tr>
<td>- Key management</td>
<td>Re-use key management already implemented</td>
<td></td>
</tr>
<tr>
<td>- Integration in test daisy-chain</td>
<td>Possible issue with the padding of test data</td>
<td>No issue</td>
</tr>
</tbody>
</table>
Thank You
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